

The banner features a blue background with a red sun on the left, a silhouette of a sailboat, and a dark blue silhouette of a city skyline with a satellite dish on the right. The text 'ACCEDE | ESCCON' is in dark blue, '2025' is in a larger blue font, and 'Seville - Spain' and '25 to 27th March' are in white. Logos for ALTER and ESA are on the left.

ACCEDE | ESCCON

2025

Seville - Spain
25 to 27th March

ALTER | esa

Radiation tolerant n- and p-channel power MOSFETs for space applications

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26.03.2025



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Infineon is a global leader in power systems and IoT

Global leader

in automotive, power management, energy efficient technologies and IoT

~58,060

employees¹

Market position

Automotive

#1

TechInsights,
April 2024

Power

#1

Omdia,
October 2024

Microcontroller

#1

Omdia,
March 2025



¹ As of 30 September 2024

Infineon leading in power systems – mastering all three key materials

- » Reliable multi sourcing of raw materials
- » World-scale fabs



- » Application understanding
- » Packaging know-how and hybridization competence

Leadership in Power Systems across all materials and technologies

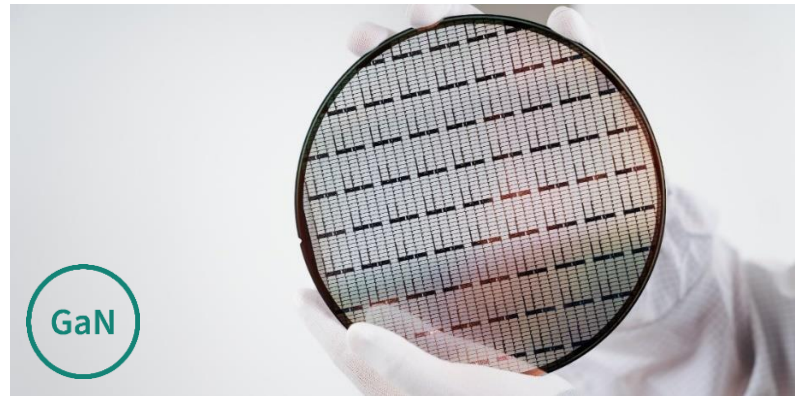
Silicon
Diode – MOSFET – IGBT – Driver – Controller



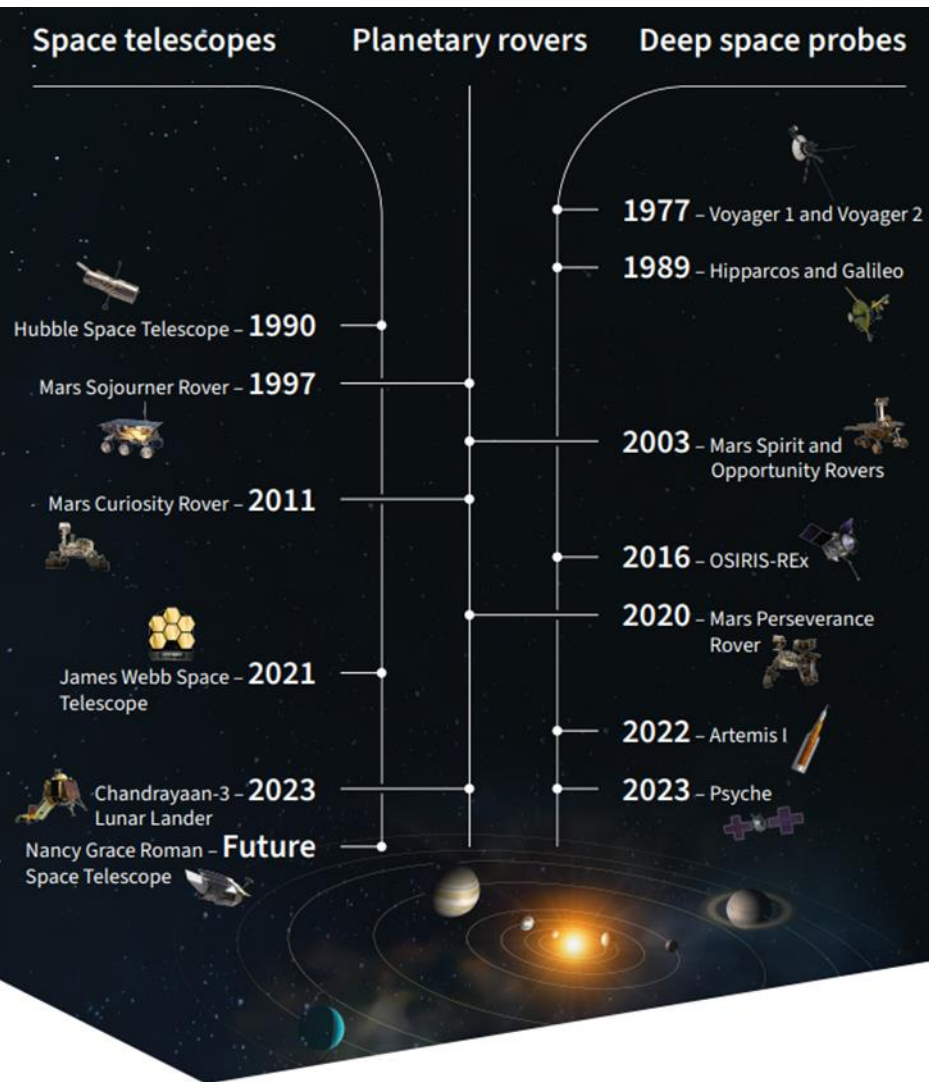
Silicon carbide
Diode – MOSFET



Gallium nitride
HEMT – Driver



Infineon has more than 50 years of space heritage



RF and power devices from Infineon are part of many missions

- First order for RH RF component received in 1977
- Some more examples in alphabetical order
 - Alphasat (Joint ESA/Inmarsat communications satellite)
 - Artemis (Advanced Relay And Technology Mission, ESA)
 - JUICE (Jupiter Icy Moons Explore, ESA, 2023)
 - Intelsat (Communication, commercial)
 - IRNSS (India Regional Navigational Satellite System, ISRO)
 - Galileo NG (Satellite navigation system, ESA, 2014-2024)
 - GPSII (Global Positioning System, NASA)
 - Mars Rover (Exploration, NASA)
 - Meteosat SG (Weather monitoring & forecasting, ESA/EUMETSAT)
 - Sentinel (Earth observation, ESA)

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Key features of new family of radiation tolerant (RT) products

- **Package**
 - Plastic with matte Tin lead finish
- **Radiation ratings** provided
 - **SEE** (Single Event Effect): **46 LET MeVcm²/mg**
 - **TID** (Total Ionization Dose): **30krad**
- **Qualified / tested according**
 - AEC-Q101
 - MIL-STD-750/883
 - ASTM E595 (outgassing)
 - MIL-STD-883 method 1009.9 (salt atmosphere)
- **Fixed production** locations
 - Chip: Infineon power factories (**Dresden, Kulim**)
 - Package: Infineon qualified assembly lines, **Asia**



Comparison with automotive grade and full space qualified party

Parameter	Automotive Grade	RT MOSFET	ESA	JANS
Package type	Plastic Encapsulated	Plastic Encapsulated	Ceramic	Ceramic
Lead finish	Pure/Matte Sn	Matte Sn *)	Au	Solder Sn/Pb or Au
Operating temperature range	-40°C to 125°C	-40°C to 125°C	-55°C to 150°C	-55°C to 150°C
Qualification	According AEC Q101	According AEC Q101	According to ESCC5000	According to MIL-PRF-19500
Electrical Testing	Automotive standard testing	Automotive standard testing	According to ESCC5000	According to MIL-PRF-19500
Screening (BI, TC, Hermeticity...)	No additional screening	No additional screening	According to ESCC5000	According to MIL-PRF-19500
Fixed Process Flow	None	Yes	Yes	Yes
SEE Testing	None	One time for technology 46 LET	One time for technology >80 LET	One time for technology >80 LET
TID Testing	None	Specified TID 30kRad	RHA by diffusion lot TID>100kRad	Wafer by wafer RHA TID > 100krad(Si)
DOC	No	On request	Yes	Yes
Traceability	No	No serialization SLDC on request	Serialization	Serialization

*) lead finish is qualified to meet class 2 of JESD 201A

Overview on qualification and radiation tests

Product qualification

- Qualification according to AEC-Q101 Rev. E
- Family qualification for PG-TO263 and PG-TO247
- Standard stress tests are applied:
 - UHAST, TC, HTGS, HTRB, ...
- ESD HBM & CDM are assured
 - HBM 1kV to <2kV
 - CDM >1kV

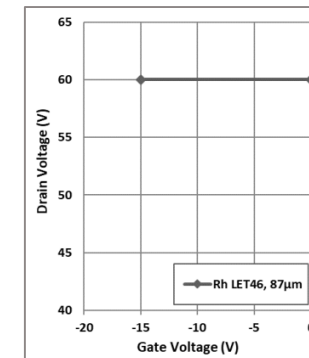
TID testing

- Irradiation according to ESCC22900 standard
- Radiation tolerance is part of the product specification
- Test conditions:

	V_{DS} [V]	V_{GS} [V]
C1	0	+12
C3	80% of VDS (48V, 120V, 200V)	0

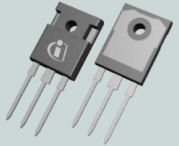


SEE testing

- Irradiation according to ESCC25100 and MIL-STD-750 test method 1080
- SEE performance published as SOA diagram in the latest datasheet



Product portfolio for power MOSFETs

– Product overview

Product	Package	Type	$U_{DS(max)}$	$R_{DSon(max)}$ @25°C	I_{Dmax} @25°C	TID	SEE	Package
BUP06CN015E-01		N	60V	15mΩ	52A	30krad	46LET	PG-TO247-3
BUP15CN027E-01		N	150V	27mΩ	98A			
BUP06CN035L-01		N	60V	35mΩ	36A			PG-TO263-3
BUP15CN060L-01		N	150V	60mΩ	106A			
BUP06CP038F-01		P	60V	38mΩ	-35A			

- Sample available for all types
- **Product status** “active and preferred”

Target applications

- Typical use cases: DC-DC Converter, Power distribution unit, load switch, PoL, Motor drive

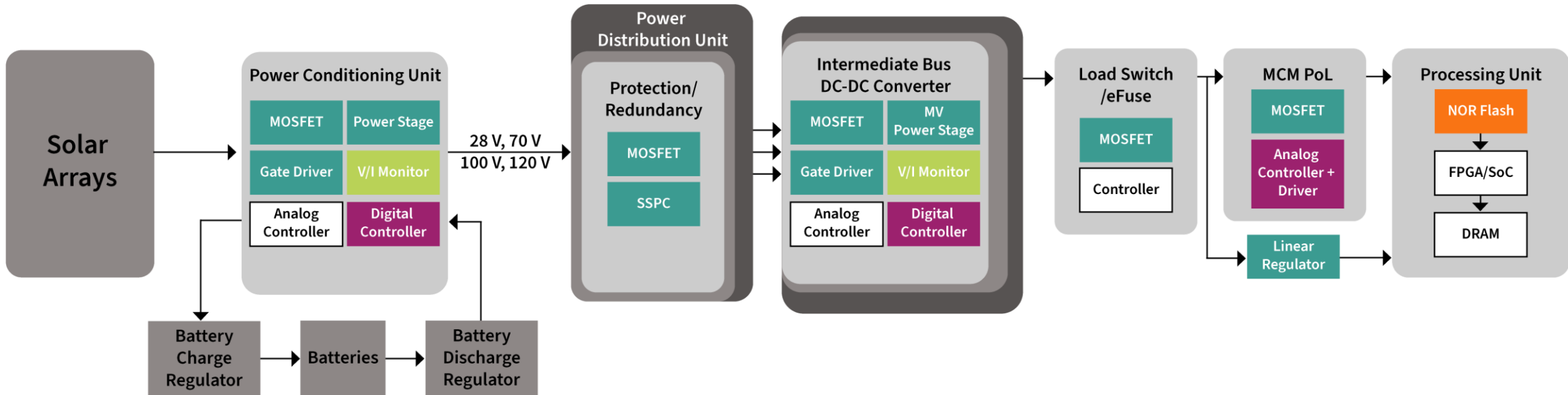


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Additional environmental tests for plastic package used in space

Salt Atmosphere Test

- This test evaluates the corrosion resistance of materials when exposed to a salt fog or spray, e.g. during transport.
- For electronics, especially those used in harsh environments this test is critical. It ensures that the product's packaging and materials can withstand corrosive environments, preventing premature failures.
- RT products passed test according MIL-STD-883 method 1009.9

Outgassing Test

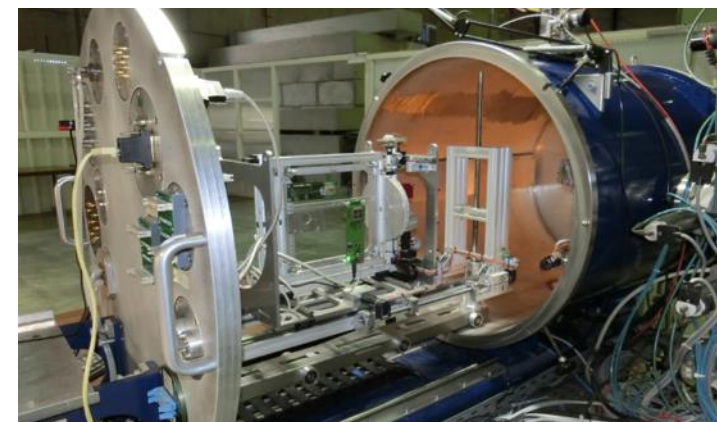
- This test measures the amount of volatile compounds that a material releases in a vacuum.
- In space applications, outgassing is a major concern because released volatiles can contaminate sensitive optical surfaces or other components.
- Understanding outgassing properties is essential for ensuring the reliability of electronics in vacuum environments, such as those found in Space
- RT product passed test according ASTM E595

SEE test set-up for RT power MOSFETS

- Test location for SEE test: Cyclotron Resource Centre (CRC) in Louvain-la-Neuve, Belgium
- Test set-up: DUT was mounted on a test PCB in line with the beam at normal incidence and irradiated while the Keithley SMUs measured device voltages and currents
- Irradiation specification: ESCC Basic Specification No. 25100 Iss. 2, Oct 2014
- SEE test criteria are shown below:
 - Ion Species: $^{103}\text{Rh}^{31+}$
 - LET: $46.1 \text{ Mev} \cdot \text{cm}^2 / \text{mg}$
 - Flux: $3e3 \text{ ions} / \text{cm}^2 / \text{s}^{-1}$
 - Fluence: $3e5 \text{ ions} / \text{cm}^2$



Source: CRC - Cyclotron Resource Centre, UCLouvain



Source: CRC - Cyclotron Resource Centre, UCLouvain

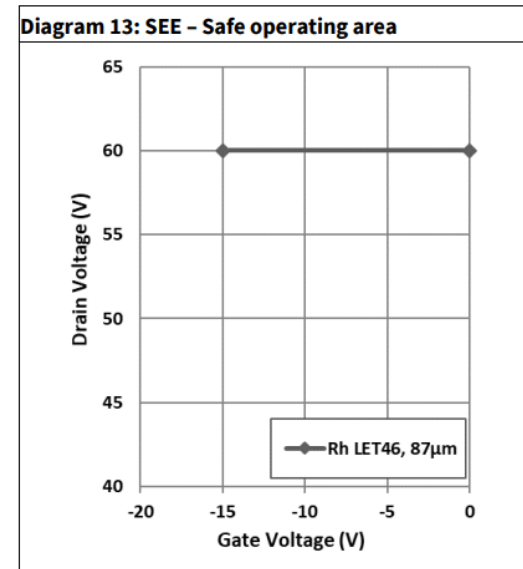
Infineon RT power MOSFET products are SEB and SEGR free

SEE performance

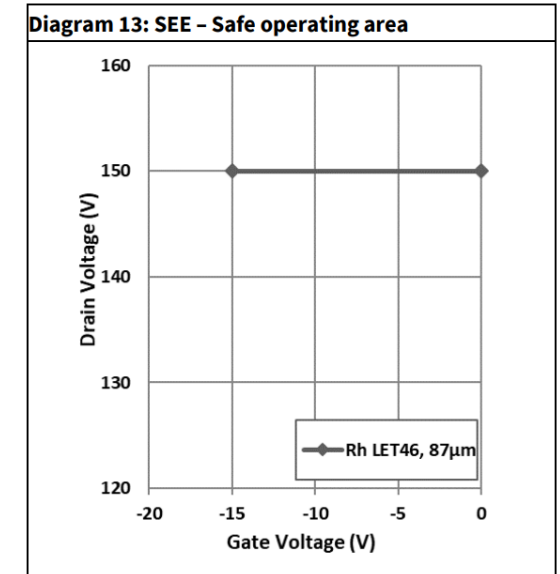
- SEE performance: The test results show that both devices are immune to single event burnout and gate rupture up to their maximum rated drain-source voltages for $LET=46.1 \text{ Mev} \cdot \text{cm}^2 / \text{mg}$
- FAIL criteria:
 - $IDS > 2\mu\text{A}$ or $IGS > 100\text{nA}$
- PIGS FAIL criteria:
 - IDS or $IGS > 100\text{nA}$
- Required PASS samples: 3

Safe operating area curves

60V n-channel SEE SOA



150V n-channel SEE SOA



TID test set-up for RT power MOSFETS

- For TID testing, devices were irradiated by a Co-60 source at the JS-9000 facility in Germany and electrical measurements were taken under the following conditions:
 - Prior and post irradiation
 - Posterior to room-temp anneal of 24 hours
 - Posterior to 168 hours of anneal at 100°C

- Irradiation specification: ESCC Basic Specification No. 22900 Iss. 5, June 2016

- Electrical bias conditions:

Electrical Bias Condition	Bias Condition	Supply voltages		
		Gate	Drain	Source
C1	Fig. 1	+12V	0V	0V
C3	Fig. 1	0	80% $V_{DS(max)}$	0V

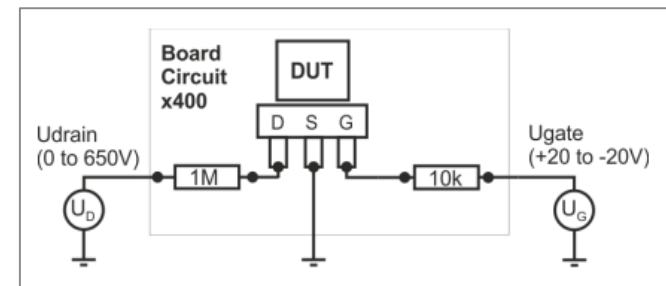


Fig. 1 Bias circuit for TID test

Infineon RT products are radiation robust up to 30krad (Si)

TID performance

- No failures occurred during TID testing, which indicates that both devices are radiation tolerant up to 30 krad (Si)
- The pass/fail criteria are the electrical test parameters as defined in the specification data sheet
- An example of this is shown on the right
 - black = no irradiation
 - red = gate bias (C1)
 - blue = drain bias (C3)
- The plot's y limits are the threshold for pass/fail in this case

Vth TID response

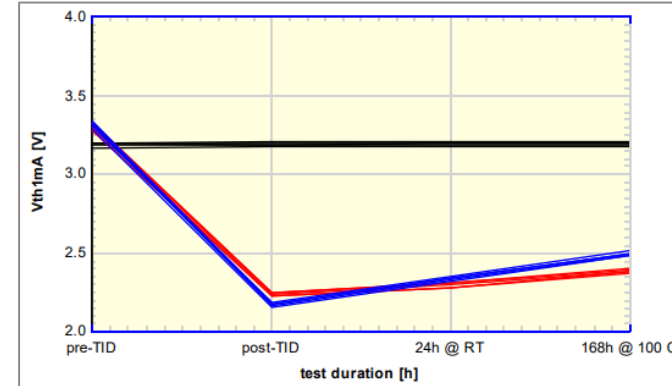


Fig. 2: 60V n-channel Vth TID response

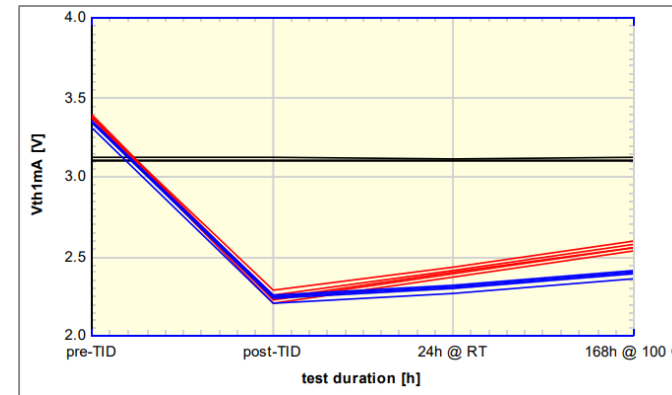
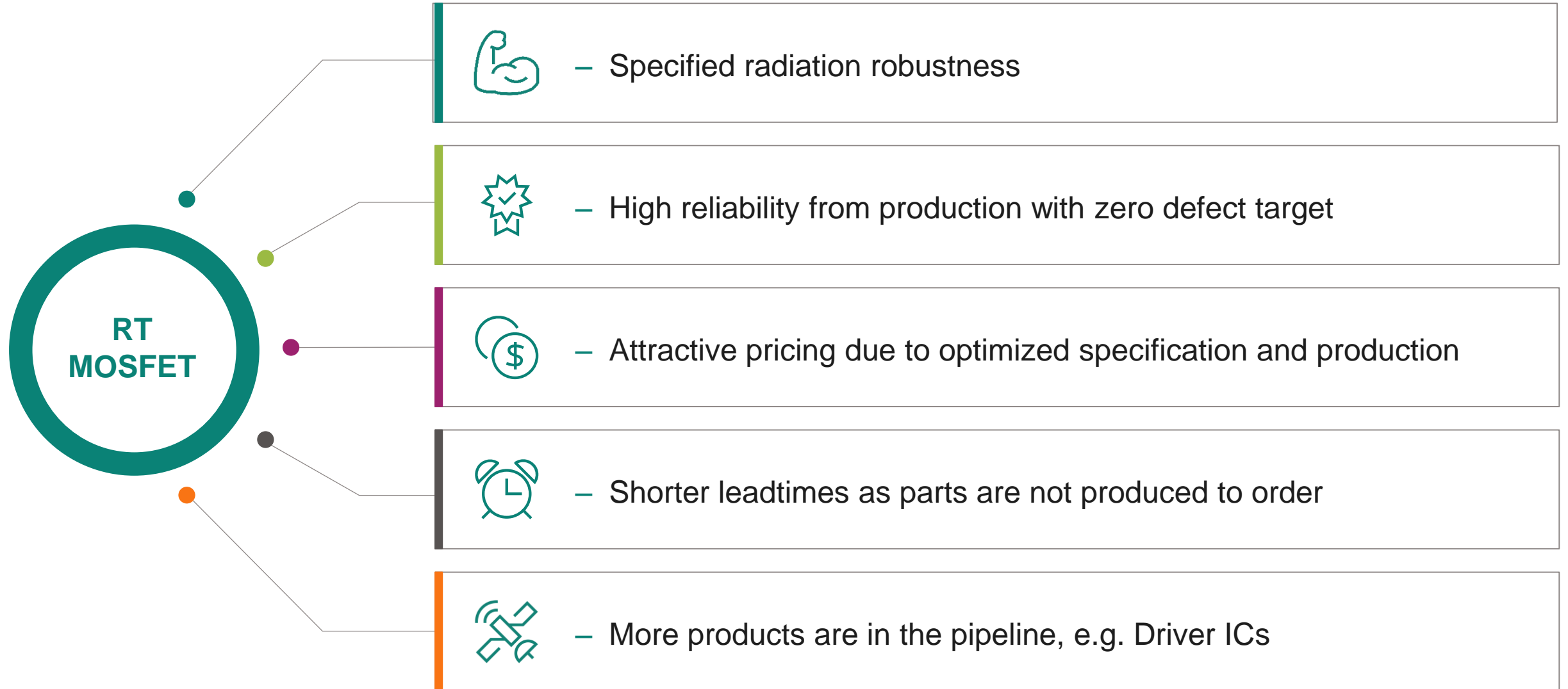


Fig. 3: 150V n-channel Vth TID response

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Summary & Outlook



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- For SEE, TID and qualification reports please contact Infineon sales or distributor to get further information

